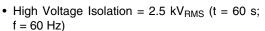


FS2KM-18-VB Datasheet N-Channel 950 V (D-S) Power MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V)	95	60
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	3.5
Q _g (Max.) (nC)	78	
Q _{gs} (nC)	10	
Q _{gd} (nC)	42	
Configuration	Sing	le

FEATURES

· Isolated Package



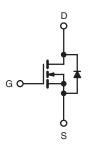




- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T	C = 25 O, unless otherw				
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V_{DS}	950	V	
Gate-Source Voltage		V_{GS}	± 20	7	
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}C$	1-	3.0		
Continuous Diain Current	$T_C = 100 ^{\circ}C$	I _D	2.3	Α	
Pulsed Drain Current ^a	I _{DM}	10			
Linear Derating Factor			0.28	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	220	mJ	
Repetitive Avalanche Currenta		I _{AR}	1.9	Α	
Repetitive Avalanche Energy ^a		E _{AR}	3.5	mJ	
Maximum Power Dissipation	T _C = 25 °C	P_{D}	35	W	
Peak Diode Recovery dV/dtc	dV/dt	1.5	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	7	
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	6-32 OF IVIS SCIEW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=115~mH, $R_G=25~\Omega$, $I_{AS}=1.9~A$ (see fig. 12). c. $I_{SD}\leq 3.6~A$, $dI/dt\leq 70~A/\mu s$, $V_{DD}\leq 600$, $T_J\leq 150~^{\circ}C$.

- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	TINGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.6	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		·					
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	950	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		1.1	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zone Ooto Wallana Busin Oomaad	1	V _{DS} = 900 V, V _{GS} = 0 V		-	-	100	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 720 \	V _{DS} = 720 V, V _{GS} = 0 V, T _J = 125 °C		-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.1 A ^b	-	3.5	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 50 V, I _D = 1.1 A ^b	1.7	-	-	S
Dynamic		·					
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V}, \\ V_{DS} = 25 \text{ V},$		-	1200	-	pF
Output Capacitance	C _{oss}			-	320	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		200	-	
Drain to Sink Capacitance	С	f = 1.0 MHz		-	12	-	
Total Gate Charge	Qg		I _D = 3.6 A, V _{DS} = 360 V, see fig. 6 and 13 ^b	-	-	78	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	10	
Gate-Drain Charge	Q _{gd}	1		-	-	42	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 450 \text{ V}, I_{D} = 3.6 \text{ A},$ $R_{G} = 12 \Omega, R_{D} = 120 \Omega,$ see fig. 10^{b}		-	14	-	- ns
Rise Time	t _r			-	25	-	
Turn-Off Delay Time	t _{d(off)}			-	90	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s			•			
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.9	А
Pulsed Diode Forward Current ^a	I _{SM}			-	-	7.6	^
Body Diode Voltage	V_{SD}	$T_J = 25$ °C, $I_S = 1.9$ A, $V_{GS} = 0$ V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T 25 °C I-	- 3.6.4 dl/dt - 100.4/usb	-	430	650	ns
Body Diode Reverse Recovery Charge	Q_{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 3.6 \text{A}, \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$			1.4	2.1	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-o			ninated by	$_{\rm S}$ and I	_D)

Notes

2

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 $\mu s;$ duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

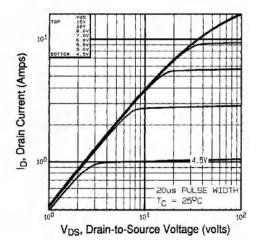


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

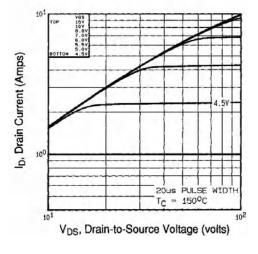


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

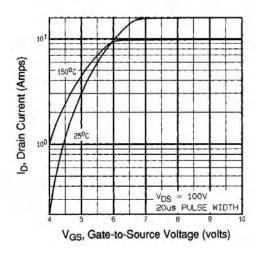


Fig. 3 - Typical Transfer Characteristics

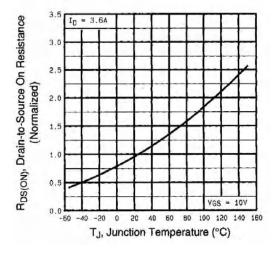


Fig. 4 - Normalized On-Resistance vs. Temperature



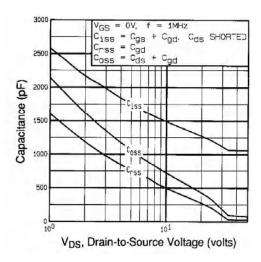


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

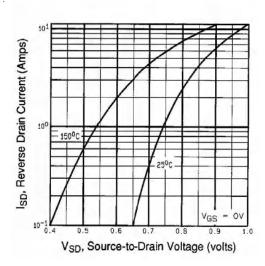


Fig. 7 - Typical Source-Drain Diode Forward Voltage

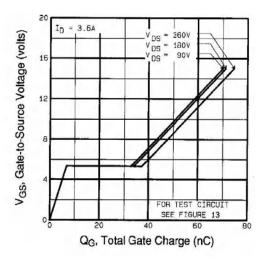


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

4

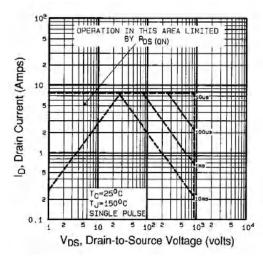


Fig. 8 - Maximum Safe Operating Area



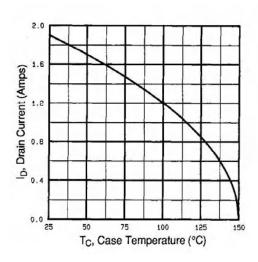


Fig. 9 - Maximum Drain Current vs. Case Temperature

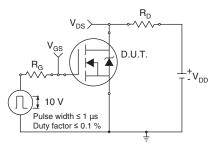


Fig. 10a - Switching Time Test Circuit

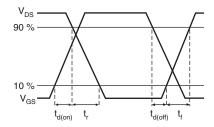


Fig. 10b - Switching Time Waveforms

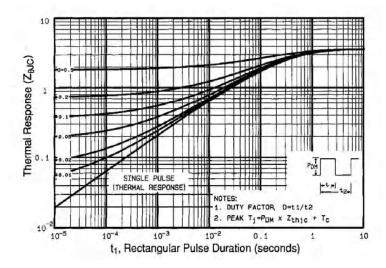


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

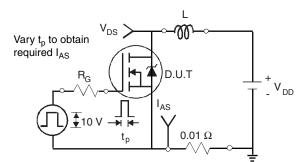


Fig. 12a - Unclamped Inductive Test Circuit

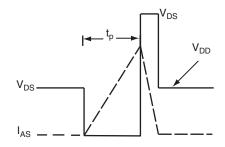


Fig. 12b - Unclamped Inductive Waveforms



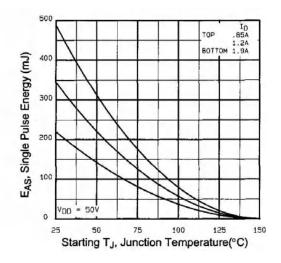


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

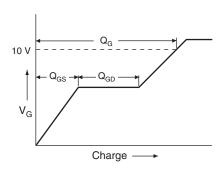


Fig. 13a - Basic Gate Charge Waveform

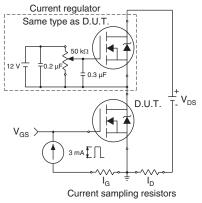
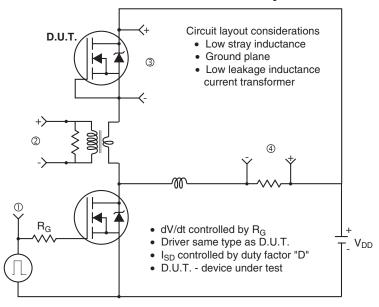


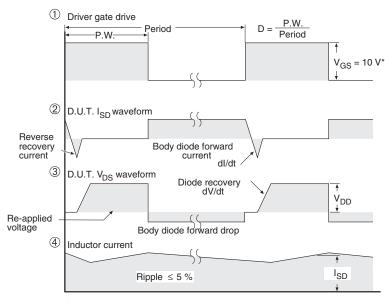
Fig. 13b - Gate Charge Test Circuit



7

Peak Diode Recovery dV/dt Test Circuit



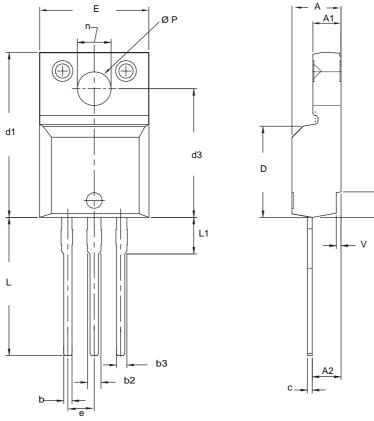


* $V_{GS} = 5 V$ for logic level devices

Fig.14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

Notes

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burst and plating thickness.

- 5. No chipping or package damage.



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